

ABSTRACT OF THE DISCLOSURE

At least two (2) inspection light beams 8 are caused to penetrate through a first and a second light beam
5 penetrating portions having the same phase of a phase shifting mask and again penetrate through the light beam penetrating portions using a reflector 3. The intensities of the reflected light beams from them are compared to each other and a defect inspection of the phase shifting mask
10 is conducted using the intensity difference.